

# POWER LOGIC 8-BIT ADDRESSABLE LATCH

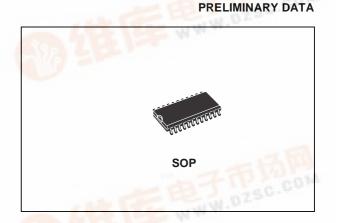
LOW R<sub>DS(on)</sub>: 1Ω TYP

- **OUTPUT SHORT-CIRCUIT PROTECTION**
- 75mJ AVAILANCHE ENERGY
- EIGHT 350mA DMOS OUTPUTS
- 50V SWITCHING CAPABILITY
- FOUR DISTINCT FUNCTION MODES
- LOW POWER CONSUMPTION

#### DESCRIPTION

This power logic 8-bit addressable latch controls open-drain DMOS transistor outputs and is general-purpose designed for storage applications in digital systems. Specific uses include working registers, serial-holding registers, and decoders or demultiplexers. This is a multifunctional device capable of operating as addressable latches or an 8-line eight demultiplexer with active-low DMOS outputs. Each open-drain DMOS transistor features an independent chopping current-limiting circuit to prevent damage in the case of a short circuit.

Four distinct modes of operation are selectable by controlling the clear (CLR) and enable (G) inputs and enumerated in the function table. In the addressable-latch mode, data at the data-in (D) terminal is written into the addressed latch. The addressed DMOS-transistor output inverts the data input with all unadressed DMOS-transistor output remaining in their previuous state. In the MOS-transistor outputs remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneus data in the latch, enable G should be



held high (inactive) while the address lines are changing. In the 8-line demoultiplexing mode, the addressed output is inverted with respectto the D input and all other output are high. In the clear mode, all outputs are high and unaffected by the address and data inputs.

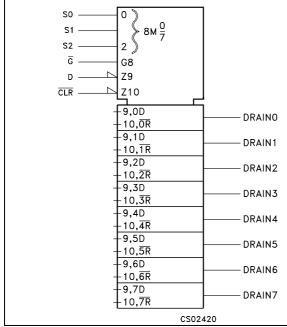
Separate power ground (PGND) and logic ground (LGND) terminals are provided to facilitate maximum system flexibility. All PGND terminals are interally connected, and each pGND terminal must be externally connected to the power system ground in order to minimize parasitic impedance. A single-point connection between LGND and PGND must be made externally in a manner that reduces crosstalk between the logi and load circuits.

The STPIC6A259 is offered in a termally enhanced SO-24 package. The STPIC6A259 is characterized for operation over the operating case temperature range -40°C to 125°C.

#### **ORDERING CODES**

Туре	Package	Comments
STPIC6A259M	SO-24 Batwing (Tube)	50parts per tube / 20tube per box
STPIC6A259MTR	SO-24 Batwing (Tape & Reel)	2500 parts per reel

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		$\square$	/]	
	DRAIN2	1	24	DRAIN1
	DRAIN3	2	23	DRAINO
	S1	3	22	S0
	LGND	4	21	V <sub>cc</sub>
RAINO	PGND	5	20	PGND
RAIN1	PGND	6	19	PGND
RAIN2	PGND	7	18	PGND
RAIN3	PGND	8	17	PGND
RAIN4	S2	9	16	CLR
RAIN5	Ē	10	15	D
	DRAIN4	11	14	DRAIN7
RAIN6	DRAIN5	12	13	DRAIN6
RAIN7				
			CS02410	

### LOGIC SYMBOL AND PIN CONFIGURATION

#### FUNCTIONAL TABLE

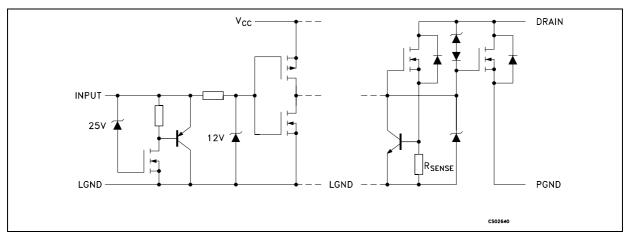
IN	INPUTS				FUNCTION
CLR	G	D	ADDRESSED DRAIN	OTHER DRAIN	FUNCTION
Н	L	Н	L	Q <sub>io</sub>	Addressable
Н	L	L	Н	Q <sub>io</sub>	Latch
Н	Н	Х	Q <sub>io</sub>	Q <sub>io</sub>	Memory
L	L	Н	L	Н	8-Line
L	L	L	Н	Н	Demultiplexer
L	Н	Х	Н	Н	Clear

#### FUNCTIONAL TABLE

SEL	ECT INP	UTS	DRAIN ADDRESSED
S2	S1	S0	DRAIN ADDRESSED
L	L	L	0
L	L	Н	1
L	Н	L	2
L	Н	Н	3
Н	L	L	4
Н	L	Н	5
Н	Н	L	6
Н	Н	Н	7

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### INPUT AND OUTPUT EQUIVALENT CIRCUITS



#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Logic Supply Voltage (See Note 2)	7	V
VI	Logic Input Voltage Range	-0.3 to 7	V
V <sub>DS</sub>	Power DMOS Drain to Source Voltage (See Note 2)	50	V
I <sub>DS</sub>	Continuous Source to Drain Diode Anode Current	1	А
I <sub>DS</sub>	Pulsed Source to Drain Diode Anode Current (See Note 3)	2	А
۱ <sub>D</sub>	Pulsed Drain Current, Each Output, All Output ON (T <sub>C</sub> =25°C)	1.1	А
۱ <sub>D</sub>	Continuous Current, Each Output, All Output ON (T <sub>C</sub> =25°C)	350	mA
۱ <sub>D</sub>	Peak Drain Current Single Output (T <sub>C</sub> =25°C) (See Note 3)	1.1	А
E <sub>AS</sub>	Single Pulse Avalanche Energy (See Note 6)	75	mJ
I <sub>AS</sub>	Avalanche Current (See Note 4)	600	mA
Pd	Continuous total dissipation ( $T_C \le 25^{\circ}C$ )	1750	mW
Pd	Continuous total dissipation ( $T_C = 125^{\circ}C$ )	350	mW
Τ <sub>J</sub>	Operating Virtual Junction Temperature Range	-40 to +150	°C
Т <sub>С</sub>	Operating Case Temperature Range	-40 to +125	°C
T <sub>stg</sub>	Storage Temperature Range	-65 to +150	°C
TL	Lead Temperature 1.6mm (1/16inch) from case for 10 seconds	260	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

#### THERMAL DATA

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Symbol	Parameter		Unit
R <sub>thj-case</sub>	Thermal Resistance Junction-case	10	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-ambient	50	°C/W

#### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min.	Max.	Unit
V <sub>CC</sub>	Logic Supply Voltage	4.5	5.5	V
V <sub>IH</sub>	High Level Input Voltage	0.85V <sub>CC</sub>	V <sub>CC</sub>	V
V <sub>IL</sub>	Low Level Input Voltage	0	0.15V <sub>CC</sub>	V
I <sub>DP</sub>	Pulse Drain Output Current (T <sub>C</sub> =25°C, V <sub>CC</sub> =5V) (see note 3, 5)	-1.8	0.6	A
t <sub>su</sub>	Set-up Time, D High Before $\overline{G} \uparrow$ (see Figure 2)	10		ns
t <sub>h</sub>	Hold Time, D High Before $\overline{G} \uparrow$ (see Figure 2)	5		ns
t <sub>W</sub>	Pulse Duration (see Figure 2)	15		ns
т <sub>с</sub>	Operating Case Temperature	-40	125	°C

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSX</sub>	Drain-to-Source breakdown Voltage	I <sub>D</sub> = 1mA	50			V
$V_{SD}$	Source-to-Drain Diode Forward Voltage	I <sub>F</sub> = 350 mA (See Note 3)		0.8	1.1	V
I <sub>IH</sub>	High Level Input Current	$V_{I} = V_{CC}$			1	μΑ
۱ <sub>IL</sub>	Low Level Input Current	$V_{I} = 0$			-1	μΑ
Icc	Logic Supply Current	I <sub>O</sub> = 0		0.5	5	mA
I <sub>ОК</sub>	Output Current at Which Chopping Starts	$T_{C} = 25^{\circ}C$ (See Note 3 and Figg. 3, 4)	0.6	0.8	1.1	A
I <sub>(nom)</sub>	Nominal Current	$V_{DS(on)} = 0.5V$ $I_{(nom)} = I_D$ $V_{CC} = 5V$ $T_C = 85^{\circ}C$ (See Note 5, 6, 7)		350		mA
۱ <sub>D</sub>	Off-State Drain Current	$V_{DS} = 40V$ $T_{C} = 25^{\circ}C$		0.1	1	μA
		$V_{DS} = 40V$ $T_{C} = 125^{\circ}C$		0.2	5	μΑ
R <sub>DS(on)</sub>	Termination Resistance	$I_D = 350 \text{mA}$ $T_C = 25^{\circ} \text{C}$		1	1.5	Ω
	(See Note 5, 6 and figg. 9, 10)	$I_D = 350 \text{mA}$ $T_C = 125^{\circ}\text{C}$		1.7	2.5	Ω

### SWITCHING CHARACTERISTICS ( $V_{CC}$ =5V, $T_{C}$ = 25°C, unless otherwise specified.)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>PHL</sub>	Propagation Dealy Time, High to Low Level Output from D	C <sub>L</sub> = 30pF I <sub>D</sub> = 350mA (See Figg. 1, 2, 11)		30		ns
t <sub>PLH</sub>	Propagation Dealy Time, Low to High Level Output from D			125		ns
t <sub>r</sub>	Rise Time, Drain Output			60		ns
t <sub>f</sub>	Fall Time, Drain Output			30		ns
t <sub>a</sub>	Reverse Recovery Current Rise Time	I <sub>F</sub> = 350mA di/dt = 20A/μs (See Note 5, 6 and Fig. 5)		100		ns
t <sub>rr</sub>	Reverse Recovery Time			300		ns

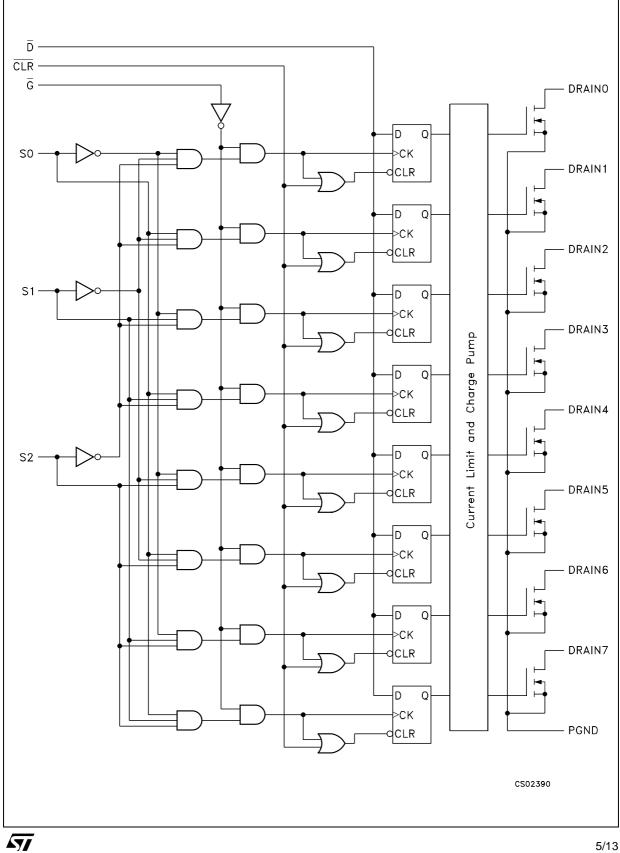
Note 1: All Voltage valuea are with respect to LGND and PGND Note 2: Each power DMOS source is internally connected to GND

Note 2: Path power Divisor Solution is and duty cycle  $\leq 2\%$ Note 4: Drain Supply Voltage = 15V, starting junction temperature (T<sub>JS</sub>) = 25°C. L = 210µH and I<sub>AS</sub> = 600mA (See Fig. 6) Note 5: Technique should limit T<sub>J</sub> - T<sub>C</sub> to 10°C maximum Note 6: These parameters are measured with voltage sensing contacts separate from the current-carrying contacts.

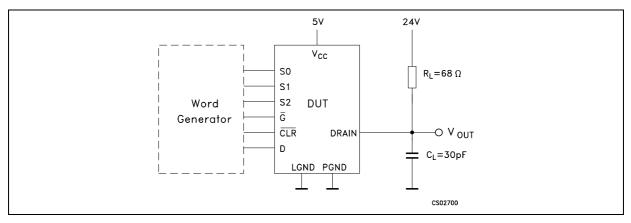
Note 7: Nominal Current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5V at  $T_c = 85^{\circ}C$ .

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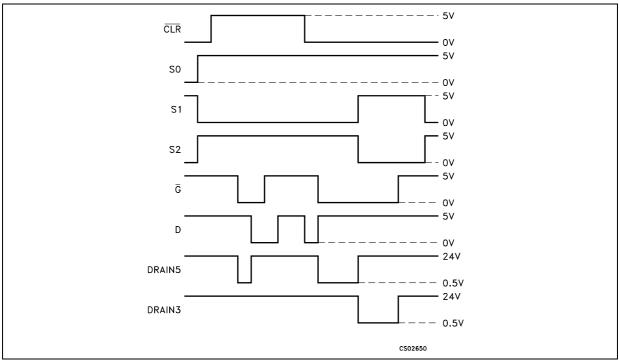
#### LOGIC DIAGRAM



#### **TYPICAL OPERATION MODE TEST CIRCUITS**



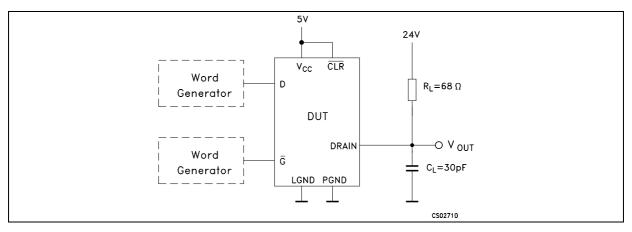
#### **TYPICAL OPERATION MODE WAVEFORMS**



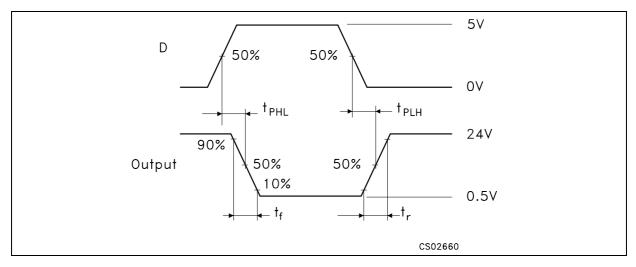
NOTE: A) The word generator has the following characteristics:  $t_r \le 10$ ns,  $t_f \le 10$ ns,  $t_W = 300$ ns, pulse repetition rate (PRR) = 5KHz,  $Z_O = 50\Omega$ B) C<sub>L</sub> includes probe and jig capacitance.

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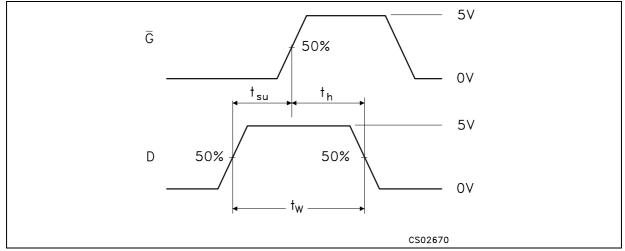
#### **TYPICAL OPERATION MODE TEST CIRCUITS**



#### SWITCHING TIME WAVEFORM

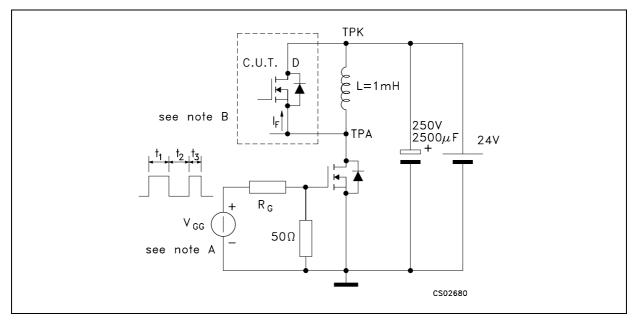


#### **INPUT SETUP AND HOLD WAVEFORM**

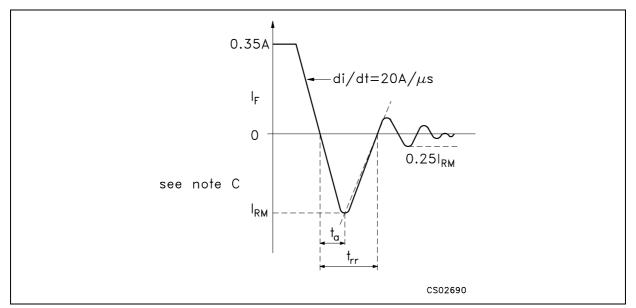


NOTE: A) The word generator has the following characteristics:  $t_r \le 10$ ns,  $t_f \le 10$ ns,  $t_W = 300$ ns, pulse repetition rate (PRR) = 5KHz,  $Z_O = 50\Omega$ B)  $C_L$  includes probe and jig capacitance.

#### **REVERSE RECOVERY CURRENT TEST CIRCUITS**



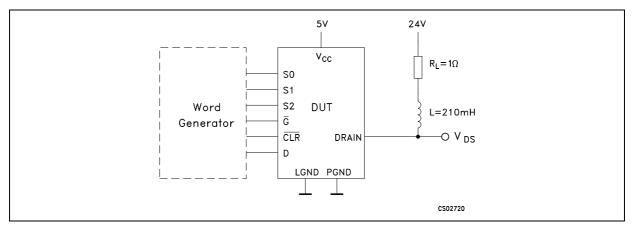
#### SOURCE DRAIN DIODE WAVEFORM



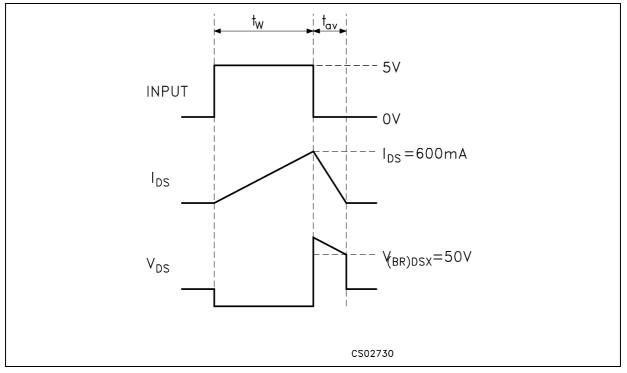
NOTE: A) The V<sub>GG</sub> amplitude and R<sub>G</sub> are adjusted for di/dt = 20A/ $\mu$ s. A V<sub>GG</sub> double-pulse trainn is used to set I<sub>F</sub> = 0.35A. where t<sub>1</sub> = 10 $\mu$ s, t<sub>2</sub> = 7 $\mu$ s and t<sub>3</sub> = 3 $\mu$ s B) The Drain terminal under test is connected to the TPK test point. All other terminals are connected together and connected to the TPA test point. C) I<sub>RM</sub> = maximum recovery current.

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#### SINGLE PULSE AVALANCHE ENERGY TEST CIRCUITS



#### SINGLE PULSE AVALANCHE ENERGY WAVEFORM



NOTE: A) The word generator has the following characteristics:  $t_f \le 10$ ns,  $t_f \le 10$ ns,  $Z_O = 50\Omega$ B) Input pulse duration, tW is increased until peak current IAS = 600 mA. Energy test level is defined as  $E_{AS} = (I_{AS} \times V_{(BR)DSX} \times t_{AV})/2 = 75$ mJ.

## **TYPICAL PERFORMANCE CHARACTERISTICS** (unless otherwise specified $T_i = 25^{\circ}C$ )

**Figure 1 :** Maximum Continuous Drain Current vs Number of Outputs Conducting Simultaneously

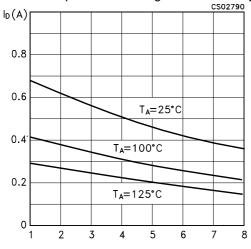


Figure 2 : Static Drain-Source ON-State Resistance vs Drain Current

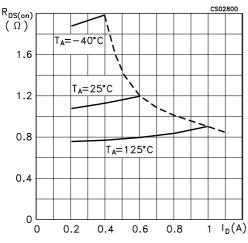


Figure 3 : MaximumPeak Drain Current vs Number of Outputs Conducting Simultaneously

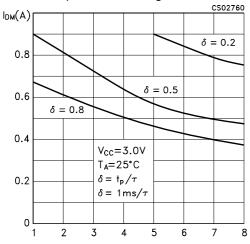


Figure 4 : Static Drain-Source ON-State Resistance vs Logic Supply Voltage

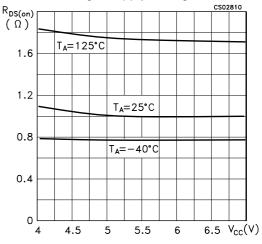


Figure 5 : Chopping Mode Characteristics

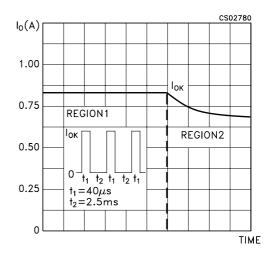
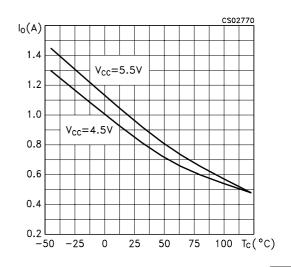
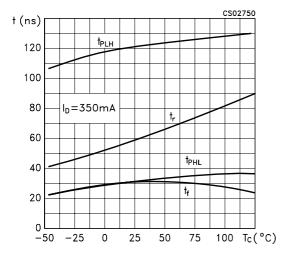


Figure 6 : Output Current vs Case Temperature



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## Figure 7 : Switching Time vs Case Temperature

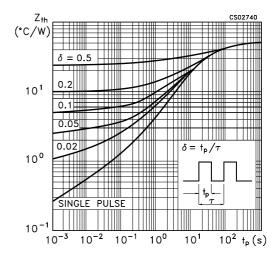
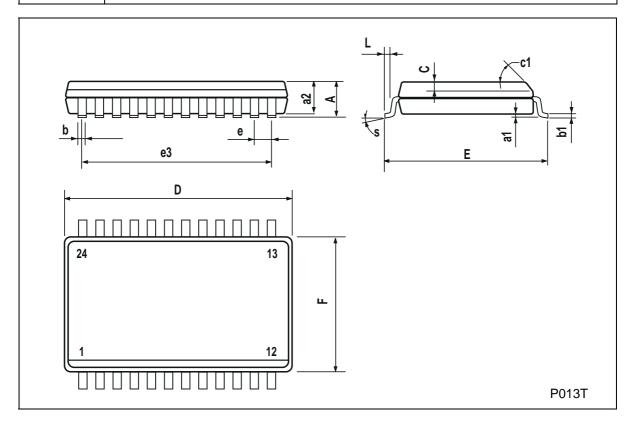


Figure 8 : Switching Time vs Case Temperature

DIM.		mm		inch		
2	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А			2.65			0.104
a1	0.10		0.20	0.004		0.007
a2			2.45			0.096
b	0.35		0.49	0.013		0.019
b1	0.23		0.32	0.009		0.012
С		0.50			0.020	
c1			45 (	(typ.)		
D	15.20		15.60	0.598		0.614
E	10.00		10.65	0.393		0.420
е		1.27			0.05	
e3		13.97			0.55	
F	7.40		7.60	0.291		0.299
L	0.50		1.27	0.19		0.050
S			8 (n	nax.)		

# SO-24 MECHANICAL DATA



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